



Docket: 500414.02

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

First Named Inventor:	Douglas D. Do and Jeff C. Johnson	Examiner:	K. Fernandez
Application No.:	09/629,022	Group Art Unit:	2881
Filing Date:	July 31, 2000		
Title:	Method and Apparatus for Measuring Features of A Semiconductor Device		

TRANSMITTAL LETTER

Commissioner for Patents  
Washington, D.C. 20231

I hereby certify that this document is being sent via First Class U. S. mail addressed to: Commissioner for Patents, Washington, D.C. 20231 on this 17 day of July, 2001.

Cynthia L. Schun  
(Name)

Dear Sir:

The following documents are enclosed in connection with the above-referenced patent application:

1. Request for Continued Examination Under 37 CFR 1.114;
2. Copy of Amendment and Response Under 37 CFR 1.116;
3. Check in the amount of \$710 for the filing fee; and
4. Return Receipt Postcard.

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In lieu of a Notice of Appeal, Applicant respectfully requests that the Examiner consider the Amendment and Response, filed May 29, 2001, in response to the Office Action made Final, dated April 17, 2001 via the enclosed Request for Continued Examination filed Under 37 CFR 1.114. A courtesy copy of the Amendment and Response filed on May 29, 2001 is enclosed for the Examiner's convenience.

Respectfully submitted,

DORSEY & WHITNEY LLP

Date:

July 17, 2001

By:

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